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0.8-micron CMOS ASCPs

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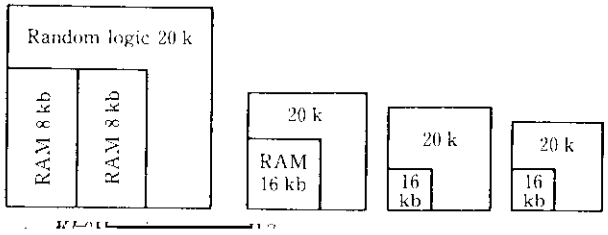
0.8-micron CMOS ASCPs*

Synopsis:

The 0.8 micron double layer metal ASCP (64 [illegible]

test pattern development time increases proportionally to the third and fourth power of any gate count.[2] From the foregoing, it is obvious that unless test pattern generation is somehow automated and facilitated

3 Technology of 0.8-μm ASCPs



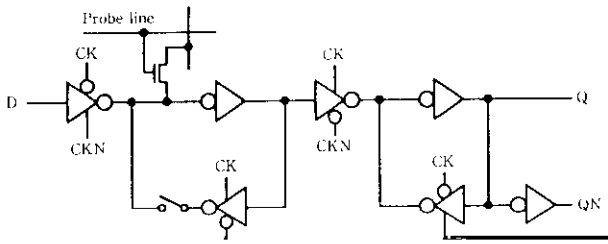
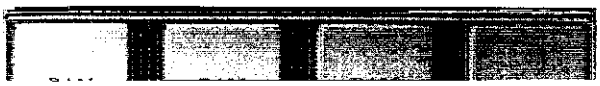


Fig. 4. Area comparison between Kawasaki Steel

The KG2H, KE2H, and KS2H series have scan registers uniquely structured on the chip to realize boundary

object-level command compatibility with Zilog's Z80 a

pixel signal



5 Conclusions